

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/721,242	DIETRICH ET AL.	
Examiner		Art Unit		Page 1 of 1
BEN C. WANG		2192		

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Abran et al., "Field Studies Using Functional Size Measurement in Building Estimation Models for Software Maintenance", March 12, 2002, John Wiley & Sons, Volume 14 Issue1, pp. 31-64.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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